

Mixed-level identification of fault redundancy in microprocessors

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A new measure for calculating multiple fault coverage of microprocessor self-test

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Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.eester.ee/record=b2150914*est